Application/Control No. 10/561,726	Applicant(s)/Pater Reexamination SPEIGHT ET AL.	nt Under
Examiner	Art Unit	
Kevin Mew	2416	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,054,317	05-2006	Jung et al.	370/395.1
*	В	US-2005/0005024	01-2005	Samuels et al.	709/238
*	υ	US-2004/0015591	01-2004	Wang, Frank Xiao-Dong	709/228
*	D	US-2003/0174700	09-2003	Ofek et al.	370/389
*	Е	US-6,831,912	12-2004	Sherman, Jon H.	370/349
*	F	US-6,535,515	03-2003	Hasegawa et al.	370/395.52
*	G	US-2005/0255850	11-2005	Auterinen, Otso	455/452.2
*	н	US-2002/0199008	12-2002	Pecen et al.	709/231
*	-	US-2004/0052234	03-2004	Ameigeiras et al.	370/338
*	7	US-2005/0141419	06-2005	Bergamasco et al.	370/230
*	К	US-2004/0071086	04-2004	Haumont et al.	370/230
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON DATENT DOCUMENTS

* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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